## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination EDEN ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,724,356	02-1988	Daehler, Max	313/522
	В	US-4,858,062	08-1989 <sup>.</sup>	Hayakawa et al.	361/225
	С	US-5,387,805	02-1995	Metzler et al.	257/147
	D	US-5,691,608	11-1997	Yamamoto et al.	315/383
	Е	US-5,955,828	09-1999	Sadwick et al.	313/310
	F	US-6,016,027	01-2000	DeTemple et al.	313/356
	G	US-6,097,145	08-2000	Kastalsky et al.	313/466
	н	US-6,139,384	10-2000	DeTemple et al.	445/24
	1	US-6,147,349	11-2000	Ray, Michael	250/338.4
	J	US-6,695,664	02-2004	Eden et al.	445/24
	К	US-6,815,891	11-2004	Eden et al.	313/618
	Ļ	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	-		-		·
	0		_			
	Р					
	ο					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.